

Question Paper

Exam Date & Time: 02-May-2019 (02:00 PM - 05:00 PM)



MANIPAL ACADEMY OF HIGHER EDUCATION

**INTERNATIONAL CENTRE FOR APPLIED SCIENCES
IV SEMESTER B.Sc (Applied Sciences) IN ENGINEERING
END SEMESTER THEORY EXAMINATION APRIL / MAY 2019
DSD USING VERILOG [IEC 244 - S2]**

Marks: 100

Duration: 180 mins.

Answer 5 out of 8 questions.

Missing data, if any, may be suitably assumed

- 1) Map the function $F(a,b,c,d,e)=abc+ab'c+e'+de$ using Xilinx XC 3000 FPGA. (5)
Determine the number of CLB's and LUT's required. Show the contents in the SRAM cell.
 - A)
 - B) Implement the following function $F=A'B+ABC'+A'B'C$ using ACT 1 logic module. (5)
 - C) Explain about semi custom ASIC (5)
 - D) Implement the given expression $F= x_1'x_3'x_4'+x_1x_2+x_3x_4$ using 4- 2 input LUT's and 1-3 input LUT. (5)
- 2) Implement 3 bit binary to gray code converter using PLA (10)
 - A)
 - B) Implement the following expression using Altera max FPGA architecture(using shared logic expander) (5)
$$F=A'CD+B'CD+AB+BC'$$
 - C) Define Transient fault, logical fault, non-logical fault with an example (5)
- 3) Find the essential test vector and selective test vector for the function (10) $F=A'B+C$ using fault table technique. Consider SA_0 and SA_1 fault in all the nodes.
 - A)
 - B) Implement $F=ABC'F+A'CD+B'CD+ABD'F+ABCDE'$ using ACT2 logic module (5)
 - C) Find the collapse ratio for the function $F=AB+BC$ using basic gates (5)
- 4) Write a Structural Verilog code for 8:1 multiplexer using 2:1 multiplexer. (10)
Write the program for entire hierarchy
 - A)
 - B) Find the test vector using path sensitization technique for the expression $F=$ (5)

$(A.B)' + (C.D)'$. Consider SA₀ fault is at input A node

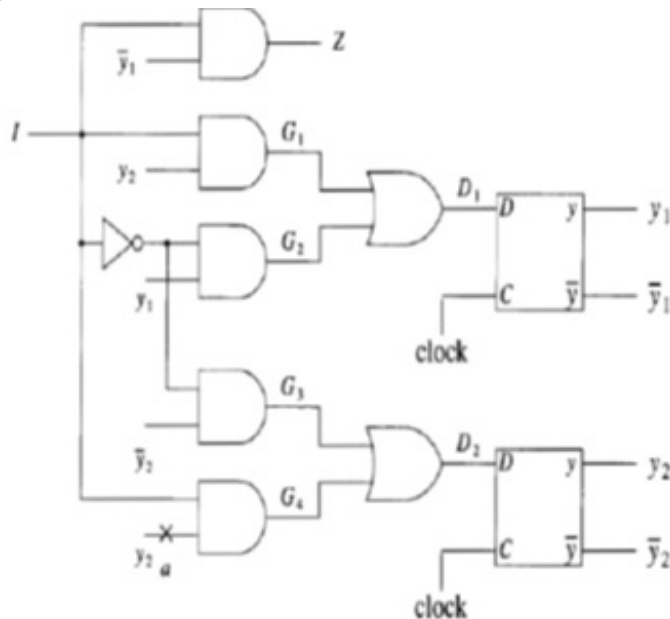
- C) Find the test vector for transparent high latch using Iterative test generator. (5)
SA₀ fault is at D input not the feedback input

- 5) Write a sequential Verilog code for 4 bit Ring counter using positive edge triggered clock (10)

A)

- B) Write a dataflow Verilog code for 2to 4 decoder with active high enable input (5)

- C) Determine the test vector for the sequential circuit shown in Fig.Q5C using ITG (5)
ITG



- 6) Explain ASIC design flow (5)

A)

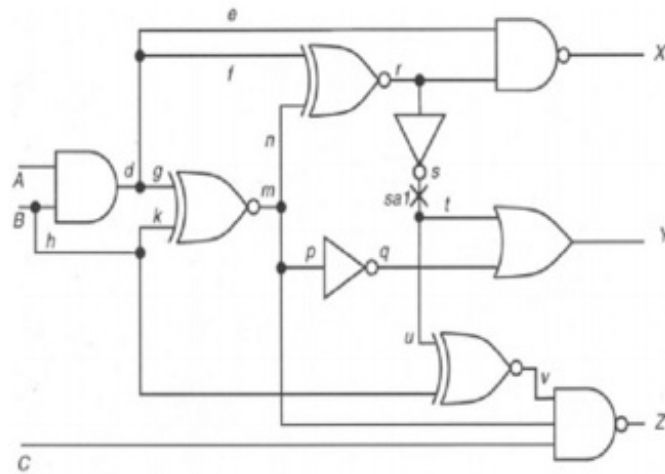
- B) Write the behavioral verilog code for 4 bit SISO shift register using if statement (10)

- C) Implement the following expression using 3*4*2 PLA (5)
 $F1(x,y,z) = \sum m(0,1,2,4,5)$ $F2(x,y,z) = \sum m(1,2,3,4,5)$

- 7) Explain the different types of identifiers used in Verilog HDL (5)

A)

- B) Find the test vector using D algorithm for the circuit shown in Fig Q7B. Consider SA1 fault. (10)



- C) Map SR latch using Xilinx XC3000 FPGA. Find the number of CLB's and LUT's required. Show the contents in SRAM cell. (5)
- 8) Write the Structural Verilog code for 4 bit universal shift register. Write the program for entire hierarchy (10)
- A)
- B) Implement half adder using ACT-1 FPGA series. How many minimum number of logic modules required to implement. (5)
- C) Write the behavioral Verilog code for Actel 2 FPGA module using if statement (5)

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